

# AbstractID: 7098 Title: Charge trapping in a prototype Active Matrix Flat Panel Dosimeter and its implications

## **Purpose:**

This work models charge trapping behavior of a prototype Active Matrix Flat Panel Dosimeter (AMFPD) using three parameters and explains a number of published observations. An understanding of charge trapping and release is necessary to estimate non-linearities in the AMFPD response due to trapping and to correct artifacts in the resulting dose image.

## **Method and Materials:**

The AMFPD consisted of an amorphous silicon flat panel imaging array operated without a phosphor screen. Fluoroscopic and radiographic modes were used to obtain a series of fixed field dosimetric measurements at different doses and dose rates. Data were acquired in order to test the assumptions upon which the model was based:

- (1) Trapped charge density in the metastable defects can be described by a stretched exponential function,  $N(t) = N_0 \exp[-(t/\tau)^\beta]$ .
- (2) Trapped charge starts to release from the trapping centers when the photodiode is recharged.
- (3) Charge release is not affected by subsequent irradiations when the dose per frame is small.
- (4) The charge trapping rate depends on bias voltage and varies slowly with dose when the dose is small.

Model stretch parameter  $\beta$ , time constant  $\tau$ , and the charge trapping rate  $p$  were determined from a fit to the pixel signal decay following irradiation. These parameters were then applied to simulate results for the AMFPD operated in fluoroscopic mode based on the above assumptions.

## **Results:**

The simulated results agreed well with the measurements. It was determined that  $\beta$  is constant for a detector array,  $\tau$  depends on bias voltage, and the charge trapping rate depends on bias voltage and dose. Furthermore, the model qualitatively explains observations reported in published papers on charge trapping.

## **Conclusion:**

A three parameter model was found to successfully describe the behavior of charge trapping and release at different values of bias voltage, frame rate, dose rate and dose.